Amendments to the Abstract:

The abstract of the disclosure has been amended in the following manner:

The invention relates to a method for x-ray examination of an object where two categories of materials are taken into consideration, comprising: the use of broad spectrum x-rays; measurements of the x-rays by bands of the spectrum; expressions ($\hat{M}$) of thicknesses or masses of the two categories of materials passed through by the x-rays, the expressions ($\hat{M}$) being functions of at least two of the measurements (mes_k) and coefficients (A); and applying a selection criterion from among the expressions ($\hat{M}$) to deduce from this an expression (final $\hat{M}$) considered true; characterized in that the selection criterion comprises a combination (f) of the expressions with weighting factors (a), and a calculation of the weighting factors such that the combination has minimal variation according to variations of the measurements.

Attachment: Replacement Sheet (clean-copy of abstract)

Abstract

The invention relates to a method for x-ray examination of an object where two categories of materials are taken into consideration, comprising: the use of broad spectrum x-rays; measurements of the x-rays by bands of the spectrum; expressions $(\hat{M})$ of thicknesses or masses of the two categories of materials passed through by the x-rays, the expressions $(\hat{M})$ being functions of at least two of the measurements (mes_k) and coefficients (A); and applying a selection criterion from among the expressions $(\hat{M})$ to deduce from this an expression (final $\hat{M}$) considered true; characterized in that the selection criterion comprises a combination (f) of the expressions with weighting factors (a), and a calculation of the weighting factors such that the combination has minimal variation according to variations of the measurements.